2832

CMI-018

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Gabriel et al.
Appl. No.	:	10/099,664
Filed	:	March, 15 2002
For	:	MODIFICATION OF SELECTIVITY FOR SENSING FOR NANOSTRUCTURE SENSING DEVICE ARRAYS
Examiner	:	unknown

Group Art Unit: 2832

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on

July 1, 2002
(Date)

David C. Cohen Reg. No. 43,554

SUBMISSION OF INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97(b)(3)

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

Applicant respectfully requests consideration of the enclosed Information Disclosure Statement and copies of the references therein in the examination of the above-referenced application. No fee is being submitted in accordance with 37 C.F.R. §1.97(b)(3).

Respectfully submitted,

Dated: July 1 2002

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	DOCKET NO. CMI-018	APPLICATION NO. 10/099,664
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANTS Gabriel et al	
	FILING DATE March 15, 2002	GROUP 2832

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
		3,676,820	7/11/1972	Taguchi	338	34	
		3,831,432	8/27/1974	Cox	73	23	
		4,101,906	8/18/1978	Dahlstrom et al.	346	75	
		4,389,658	6,21,1983	Perna et al.	346	140	
		4,542,640	9/24/1985	Clifford	73	23	
		4,759,210	7/26/1988	Wohltjen	73	23	
		5,571,401	11/5/1996	Lewis et al.	205	787	
		5,877,580	3/2/1999	Swierkowski	310	328	
		6,289,328	09/11/2001	Shaffer	706	20	
		6,312,097	11/6/2001	Brugman	347	40	
		6,321,588	11/27/2001	Bowers et al.	73	24.01	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
		WO 01/44796 A1	11/15/2000	PCT	G01N	27/12		
		WO 01/03208 A1	1/11/2001	PCT	H01L	45/00		
		WO 02/48701	6/20/02	PCT	G01N	27/00		

EXAMINER	DATE CONSIDERED

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

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EXAMINER INITIAL		OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
		Bachtold, A; Hadley, P; Nakanishi, T; Dekker, C; Science 294 (2001) p. 1317.
		Bahr, J.L., Tour, J., "Highly Functionalized Carbon Nanotubes Using in situ Generated Diazonium Compounds," (2001) p. 3823.
		Bahr, J.L., Yang, J., Kosynkin, D., Bronikowski, M., Smalley, R., Tour, J., "Functionalization of Carbon Nanotubes by Electrochemical Reduction of Aryl Diazonium Salts: A Bucky Paper Electrode", J. Am. Chem. Soc. 123 (2001) p. 6536.
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		Derycke, V; Martel, R; Appenzeller, J; Avouris, P., Nano Letters 1 (2001) p. 453.
		Hirsch, A., "Functionalization of Single-Walled Carbon Nanotubes," Angew. Chem. Int. Ed. 41 (2002) p. 1853.
		Kong, J, Franklin, N., Zhou, C., Chapline, M., Peng, S, Cho, K., Dai, H., "Nanotube Molecular Wires as Chemical Sensors," Science 287 (2000) p. 622.
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		Tans, S; Verschueren, A; Dekker, C; Nature 393 (1998) p. 49
		Zhang, Y; Dai, H; Applied Physics Letters 77 (2000) p. 3015.
		Zhang, Y; Franklin, N.W.; Chen R.J.; Dai, H; Chemical Physics Letters 331 (2000) p. 35.

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